SHEET 1 OF

Substitute for form 1449A/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

ATTORNEY'S DKT NO.	APPLICATION NO.	0	
015780-041 (CIB-1660)		77	
APPLICANT	.		
Patrick P. Naulleau		So	
FILING DATE	GROUP	J.	
August 30, 2001		1 20	
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Examiner Signature	Alan Ma	, thew	3	Date Considered	8	7-200	3	